

Notice of References Cited	Application/Control No. 10/541,815		Applicant(s)/Patent Under Reexamination GERLT ET AL.	
	Examiner MATTHEW W. SUCH		Art Unit 2891	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,447,879	09-2002	Sakurai et al.	428/161
*	B	US-6,958,270	10-2005	Misra et al.	438/257
*	C	US-6,908,536	06-2005	Beckmann, Udo	204/412
*	D	US-4,717,673	01-1988	Wrighton et al.	436/68
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Roth, K.M., et al. "Characterization of Charge Storage in Redox-Active Self-Assembled Monolayers." LANGMUIR, Vol. 18 (2002): pp. 4030-4040.
*	V	Roth, K.M., et al. "Molecular Approaches Toward Information Storage Based on the Redox Properties of Porphyrins in Self-Assembled Monolayers." J. VAC. SCI. TECHNOL. B, Vol. 18, No. 5 (Sep/Oct 2000): pp. 2359-2364.
	W	Ruzyllo, J. SEMICONDUCTOR GLOSSARY: AN INTRODUCTION TO SEMICONDUCTOR TECHNOLOGY. Prosto Multimedia Publishing: State College (2004): pp. 103.
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.